

**Search Notes****Application/Control No.**

10/620,862

**Examiner**

BENJAMIN P. GEIB

**Applicant(s)/Patent under  
Reexamination**

ANVIN ET AL.

**Art Unit**

2181

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR